

<b>Notice of References Cited</b>	Application/Control No. 10/722,855	Applicant(s)/Patent Under Reexamination VAN NIEUWSTADT ET AL.	
	Examiner Tu M. Nguyen	Art Unit 3748	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,679,051	01-2004	van Nieustadt et al.	60/286
*	B	US-6,679,052	01-2004	Nakatani et al.	60/297
*	C	US-2003/0168116	09-2003	Brenner et al.	137/875
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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